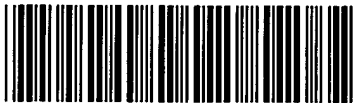


Search Notes**Application/Control No.**

10/604,343

Examiner

Thien M. Le

**Applicant(s)/Patent under
Reexamination**

CHANG ET AL.

Art Unit

2876

SEARCHED

Class	Subclass	Date	Examiner
235	472.01		
	462.01		
	462.33		
	462.43		
	454		
	494		
	483		
	479		
	475	12/12/2005	LTM

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR